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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Filing Date	March 13, 2000 Meier, Rudolf et. al.		
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				Examiner Name	H. Akhavannik		
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ATTORNEY'S DET NO MAY INFORMATION DISCOSUR 030705-164 APPLICANT Rudolf MEIER et al. Group 2700 CITATION FILING DATE GROUP PTO-1449 March 13, 2000 Unassigned ENT DOCUMENTS **EXAMINER'S** FILING DATE INITIALS PATENT NO. DATE SUBCLASS NAME CLASS 5,544,256 08/1996 Brecher et al. 382 149 FOREIGN PATENT DOCUMENTS **EXAMINER'S** Translation INITIALS PATENT NO. DATE COUNTRY **CLASS** SUBCLASS No 36 39 636 05/1988 Germany X 0 491 954 07/1992 **Europe** English 2 701 766 08/1994 France X 2 253 697 09/1992 **Great Britain** in English OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

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